

<b>Notice of References Cited</b>	Application/Control No. 09/580,343	Applicant(s)/Patent Under Reexamination BENAGE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP 59131614 A	07-1984	Japan	SHIMIZU et al.	C08F299/04
	P	JP 60088023 A	05-1985	Japan	TAKAMIZAWA et al.	C08F299/02
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**NON-PATENT DOCUMENTS**

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	U	Derwent abstract: Derwent ACC-No. 1976-74973X, of JP 51095490 A (1976.08.21)
	V	Derwent abstract: Derwent ACC-No. 1984-222677, of JP 59131614 A (1984.07.28)
	W	Japanese Patent Office abstract of JP 60088023A (1985.05.17)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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